CLAIMS

What is claimed is:

1.   A testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:

storing an enhanced reliability testing flag associated with a unique identification code of each
        integrated circuit device of the plurality of integrated circuit devices for indicating
        whether each integrated circuit device requires enhanced reliability testing;

automatically reading the unique identification code of each integrated circuit device of the
        plurality of integrated circuit devices;

accessing the enhanced reliability testing flag stored for each unique identification code of each
        integrated circuit device;

sorting the plurality of integrated circuit devices in accordance with whether their enhanced
        reliability testing flag indicates they are in need of the enhanced reliability testing; and

performing the enhanced reliability testing for the integrated circuit devices requiring the
        enhanced reliability testing.

2.   A reliability testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:

storing an reliability testing flag associated with a unique identification code of each integrated
        circuit device of the plurality of integrated circuit devices for indicating whether each
        integrated circuit device requires further reliability testing;

automatically reading the unique identification code of each integrated circuit device of the
        plurality of integrated circuit devices;

accessing the reliability testing flag stored for each unique identification code of each integrated
        circuit device;

sorting the plurality of integrated circuit devices in accordance with whether their reliability
        testing flag indicates they are in need of the further reliability testing; and

performing further reliability testing for the integrated circuit devices requiring the further
        reliability testing.

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3.   A manufacturing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:

storing a reliability testing flag associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;

automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;

accessing the reliability testing flag stored for each unique identification code of each integrated circuit device;

sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and

performing further reliability testing for the integrated circuit devices requiring the further reliability testing.